



# THz Multi-Layer Imaging via Nonlinear Inverse Scattering

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# **THz-TDS (THz Time-Domain Spectroscopy)**

### **Raster Scanning Mode**



- Normal incident THz beam
- Mechanically move THz transceiver or samples
- Spot size: 1-mm radius at 1 THz
- Pulse width: 1-5 ps
- Sampling frequency: up to 5 THz
- Scanning rate: 100 Hz to 1000 Hz

THz-TDS @ Osaka Univ.



### **Compressed Scanning Mode**



- Collimated THz beam
- Spatial light modulator (SLM) at THz band
- Focusing lens before THz detector
- No mechanical scanning
- Need random masks





### **Raster Scanning**



### **Compressed Scanning**



Examples:

- Books
- Old paintings
- Biomedical diagnosis
- Package inspection
- Security screening













# Ref. [1]: THz images of the front and back of the first sheet of paper



### Ref. [3]: MIT THz See-Through Book

#### Measured time-domain E-field amplitude on page 7-9



# Ref. [2]: THz image (c) of the painting *La oracion en el huerto*



Fig. 3. a. Second detail of the painting La oración en el huerto. b. the infrared image of the detail. c. the THz record of the detail

[1] G. C. Walker, et al., "Terahertz deconvolution," Optics Express, vol. 20, no. 25, pp. 27230–27241, Dec. 2012.

[2] C. L. K. Dandolo et al., "Contribution of terahertz time-domain analysis to art history: The case of the paintings of the Santo Entierro de Nuestro Señor Jesucristo altarpiece," 42nd IRMMW-THz, Cancun, Mexico, 2017

[3] A. Redo-Sanchez, et al., "Terahertz time-gated spectral imaging for content extraction through layered structures," Nature Communications, vol. 7, pp. 1–7, Sept. 2016.





### Our own experiment at Osaka University









The shadow effect of non-overlapping content for front layers to deep layers





- What is inverse scattering: Reconstruction of the spatial permittivity of an object by probing it using electromagnetic or acoustic waves and measuring the scattered wavefield around the object.
- Acquisition modes:
  - Transmission mode
  - Reflection mode
- How to solve inversion scattering for reflection regime:
  - Ray-tracing model [1]
  - First order Born approximation [2]
  - Rytov approximation [3]
  - Reverse-time migration [4]
- Problem?
  - Fails to account for the complex interaction between the wavefield and the material properties that result in multiple scattering.
  - Requires an accurate initial target model to enable the inversion and generally suffers from poor reconstruction quality especially when the material is inhomogeneous or contains highly scattering objects.

<sup>[1]</sup> G. H. Spencer et al., "General ray-tracing procedure," JOSA, vol. 52, no. 6, pp. 672–678, 1962.

<sup>[2]</sup> A. J. Devaney, "Inversion formula for inverse scattering within the Born approximation," Opt. Lett. 7, 111-112, 1982

<sup>[3]</sup> A. J. Devaney, "Inverse-scattering theory within the Rytov approximation," Optics letters, vol. 6, no. 8, pp. 374–376, 1981.

<sup>[4]</sup> E. Baysal et al., "Reverse time migration," Geophysics, vol. 48, no. 11, pp. 1514–1524, 1983.



### **Ray-tracing model**

Ray-tracing model [1]  $x(t) = \rho_1 s \left( t - 2\frac{z_0}{c} \right) + \rho_2 (1 - \rho_1^2)^2 s \left( t - 2\frac{z_0}{c} - 2\frac{n_2 d_1}{c} - 2\frac{d_2}{c} \right)$ 



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### overlapping content

n<sub>2</sub>

E<sub>6</sub>

d₁→

E2

n₁

E<sub>7</sub>

 $Z_0$ 

E₁

E<sub>0</sub>

 $E_3$ 

E4

 $d_2$ 



[1] G. H. Spencer et al., "General Ray-Tracing Procedure<sup>†</sup>," J. Opt. Soc. Am. 52, 672-678 (1962).

[2] P. Wang et al., "Multi-Layer Terahertz Imaging of Non-Overlapping Contents," 2018, pp. 652-656.

for a greener tomorrow

Ray Tracing [2]

n2

← d₁ →

E<sub>5</sub>

n1

z





Matrix form:  

$$\boldsymbol{u}(\omega) = \boldsymbol{u}_{in}(\omega) + \boldsymbol{G}(\omega) \operatorname{Diag}(\boldsymbol{d}) \boldsymbol{u}(\omega)$$
  
 $\boldsymbol{y}(\omega) = \boldsymbol{h}^{T}(\omega) \operatorname{Diag}(\boldsymbol{u}(\omega))\boldsymbol{d} + \boldsymbol{e}(\omega)$ 

Inverse Problem:

$$\min_{\boldsymbol{d},\boldsymbol{u}} \sum_{\boldsymbol{\omega}} \frac{1}{2} \left\| \boldsymbol{y}(\boldsymbol{\omega}) - \boldsymbol{h}^{T}(\boldsymbol{\omega}) \operatorname{Diag}(\boldsymbol{u}(\boldsymbol{\omega})) \boldsymbol{d} \right\|_{2}^{2} + \mathcal{R}(\boldsymbol{d})$$
  
s. t.  $\boldsymbol{u}(\boldsymbol{\omega}) = \left( \boldsymbol{I} - \boldsymbol{G}(\boldsymbol{\omega}) \operatorname{Diag}(\boldsymbol{d}) \right)^{-1} \boldsymbol{u}_{in}(\boldsymbol{\omega})$ 

 $d(r) = \epsilon(r) - \epsilon_b$ : dielectric permittivity of background k: THz wavenumber in vacuum  $g(r) = -\frac{i}{2k_b}e^{-ik_b|r|}$ : 1D free space Green's function  $k_b = k\sqrt{\epsilon_b}$ : wave number of the background medium  $\epsilon_b$ : permittivity of the background h(r): Green's function of the receiver







### **Proposed Approach**

Incremental frequency inversion framework:

for 
$$n = 1, ..., N_{\omega}$$
, and  $\lambda_i = (0,1]$ ,  
 $(\boldsymbol{d}_n, \boldsymbol{u}^*) \triangleq \arg\min_{\boldsymbol{d}, \boldsymbol{u}} \mathcal{D}_{\omega}(\boldsymbol{d}, \boldsymbol{u}_n) + \sum_{i=1}^{n-1} \lambda_i \mathcal{D}_i(\boldsymbol{d}, \boldsymbol{u}_i) + \mathcal{R}(\boldsymbol{d})$   
s.t.  $\boldsymbol{u}(\omega) = \left(\boldsymbol{I} - \boldsymbol{G}(\omega) \operatorname{Diag}(\boldsymbol{d})\right)^{-1} \boldsymbol{u}_{in}(\omega)$ 

where, 
$$\mathcal{D}_{\omega}(\boldsymbol{d}, \boldsymbol{u}) \triangleq \sum_{\omega} \frac{1}{2} \| y(\omega) - \boldsymbol{h}^{T}(\omega) \text{Diag}(\boldsymbol{u}(\omega)) \boldsymbol{d} \|_{2}^{2}$$

Total-variation regularization:

 $\begin{aligned} \mathcal{R}(\boldsymbol{d}) &\triangleq \tau \| D\boldsymbol{d} \|_1 \\ D: \text{ discrete finite difference operator in 1D} \\ \tau > 0 \end{aligned}$ 



## Simulation with synthetic data (I)



Synthetic validation on a three-layer sample pixels with dielectric permittivity profiles of (a) [3; 3; 8], (b) [3; 8; 3]



## Simulation with synthetic data (II)





effects

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and our shadow removal using our proposed method



# Simulation with synthetic data (III)



The sliced view of the layered structure: ground truth, shadow effects and our shadow removal using our proposed method for non-overlapping and overlapping content with white Gaussian noise (variance 0.1)

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MITSUBISHI

Changes for the Better





- The shadow effect in the THz-TDS multi-layer image has been removed by using nonlinear inverse scattering model by capturing the interaction between the dielectric permittivity profile and the THz wavefield.
- The proposed method recovers the multi-layer structure by solving a 1D nonlinear inverse scattering model via an iterative and sequential optimization over frequencies.
- Numerical results shows the effectiveness of the proposed.





Thank you